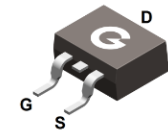
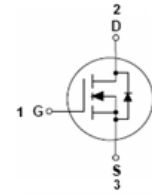


### Features

- Super low gate charge
- Green device available
- Excellent  $C_{dv} / d_t$  effect decline
- Advanced high cell density trench technology

HF



TO-263

### Mechanical Data

- Case: TO-263
- Molding Compound: UL Flammability Classification Rating 94V-0
- Terminals: Matte tin-plated leads; solderability-per MIL-STD-202, Method 208

### Ordering Information

Part Number	Package	Shipping Quantity	Marking Code
BL045N10B	TO-263	50pcs / Tube & 800pcs / Tape & Reel	045N10B

### Maximum Ratings (@ $T_A = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Value	Unit
Drain-to-Source Voltage	$V_{DSS}$	100	V
Gate-to-Source Voltage	$V_{GSS}$	$\pm 20$	V
Continuous Drain Current ( $T_C = 25^\circ\text{C}$ ) <sup>*1</sup>	$I_D$	180	A
Continuous Drain Current ( $T_C = 100^\circ\text{C}$ ) <sup>*1</sup>	$I_D$	110	A
Pulsed Drain Current <sup>*2</sup>	$I_{DM}$	450	A
Single Pulse Avalanche Energy <sup>*3</sup>	$E_{AS}$	665	mJ

### Thermal Characteristics

Parameter	Symbol	Value	Unit
Power Dissipation ( $T_C = 25^\circ\text{C}$ )	$P_D$	284	W
Thermal Resistance Junction-to-Air <sup>*1</sup>	$R_{\theta JA}$	50	$^\circ\text{C/W}$
Thermal Resistance Junction-to-Case <sup>*1</sup>	$R_{\theta JC}$	0.44	$^\circ\text{C/W}$
Thermal Resistance Junction-to-Lead <sup>*1</sup>	$R_{\theta JL}$	0.34	$^\circ\text{C/W}$
Operating Junction Temperature Range	$T_J$	-55 ~ +150	$^\circ\text{C}$
Storage Temperature Range	$T_{STG}$	-55 ~ +150	$^\circ\text{C}$

### Electrical Characteristics (@ T<sub>A</sub> = 25°C unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
<b>Static Characteristics</b>						
V <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	100	-	-	V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 100V, V <sub>GS</sub> = 0V, T <sub>C</sub> = 25°C	-	-	1	μA
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 100V, V <sub>GS</sub> = 0V, T <sub>C</sub> = 55°C	-	-	5	μA
I <sub>GSS</sub>	Gate-Body Leakage Current	V <sub>GS</sub> = ±20V, V <sub>DS</sub> = 0V	-	-	±100	nA
<b>On Characteristics</b>						
R <sub>DS(ON)</sub>	Static Drain-Source On-resistance *2	V <sub>GS</sub> = 10V, I <sub>D</sub> = 50A	-	3.5	4.5	mΩ
		V <sub>GS</sub> = 10V, I <sub>D</sub> = 2A	-	3.4	4.5	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	2	-	4	V
<b>Dynamic Characteristics</b>						
C <sub>ISS</sub>	Input Capacitance	V <sub>GS</sub> = 0V	-	5678	-	pF
C <sub>OSS</sub>	Output Capacitance	V <sub>DS</sub> = 25V	-	673	-	
C <sub>RSS</sub>	Reverse Transfer Capacitance	f = 1.0MHz	-	27	-	
<b>Switching Characteristics</b>						
t <sub>d(ON)</sub>	Turn-on Delay Time	V <sub>DD</sub> = 50V V <sub>GS</sub> = 10V R <sub>G</sub> = 4.7Ω I <sub>D</sub> = 30A	-	25	-	ns
t <sub>r</sub>	Turn-on Rise Time					
t <sub>d(OFF)</sub>	Turn-Off Delay Time					
t <sub>f</sub>	Turn-Off Fall Time					
Q <sub>G</sub>	Total Gate-Charge	V <sub>DD</sub> = 50V	-	83	-	nC
Q <sub>GS</sub>	Gate to Source Charge	V <sub>GS</sub> = 10V	-	22	-	
Q <sub>GD</sub>	Gate to Drain (Miller) Charge	I <sub>D</sub> = 40A	-	19	-	
<b>Source-Drain Diode Characteristics</b>						
V <sub>SD</sub>	Diode Forward Voltage *2	I <sub>SD</sub> = 30A, V <sub>GS</sub> = 0V, T <sub>J</sub> = 25°C	-	-	1.2	V
I <sub>SD</sub>	Source-Drain Current(Body Diode) *1,4		-	-	180	A
I <sub>SDM</sub>	Pulsed Source-Drain Current(Body Diode) *2,4		-	-	450	A
trr	Reverse Recovery Time	T <sub>J</sub> = 25°C, I <sub>F</sub> = 30A	-	71	-	ns
Qrr	Reverse Recovery Charge	di / dt = 100A / μs	-	144	-	nC

Notes:

1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper
2. The data tested by pulsed, pulse width ≤ 300μs, duty cycle ≤ 2%
3. The EAS data shows Max. rating. The test condition is V<sub>DD</sub> = 25V, V<sub>GS</sub> = 10V, L = 0.5mH
4. The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub>, in real applications, should be limited by total power dissipation

Ratings and Characteristics Curves (@  $T_A = 25^\circ\text{C}$  unless otherwise specified)

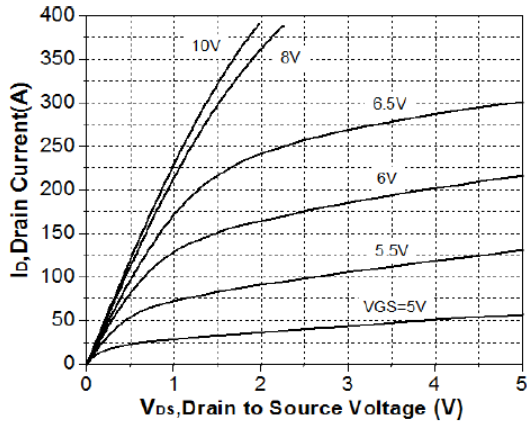


Figure 1. On-Region Characteristics

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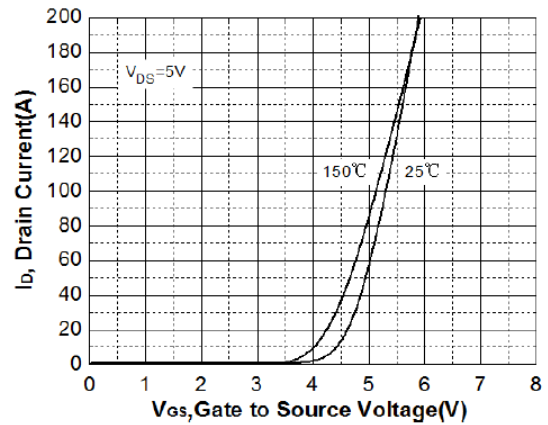


Figure 2. Transfer Characteristics

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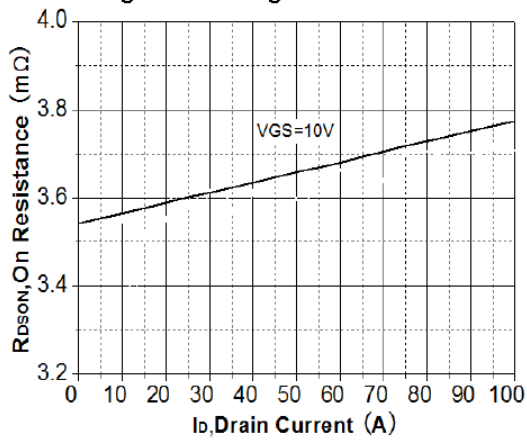


Figure 3. On-Resistance Variation vs Drain Current

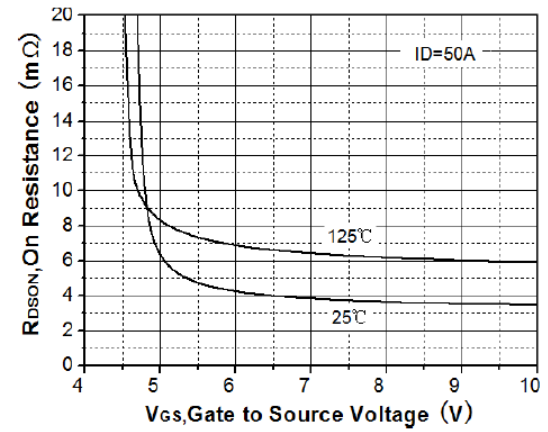


Figure 4. On-Resistance Vs Gate to Source Voltage

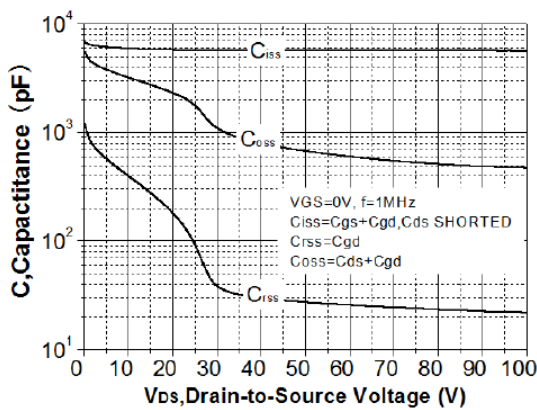


Figure 5. Capacitance Characteristics

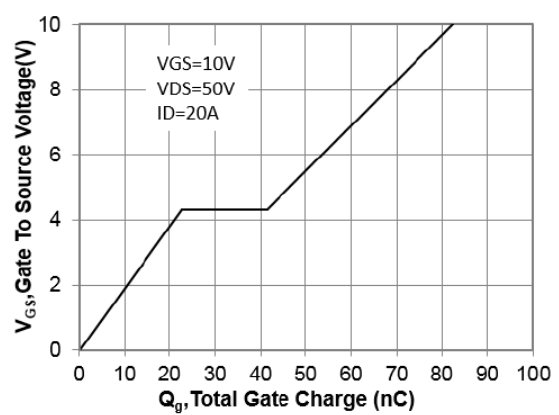


Figure 6. Gate Charge Characteristics

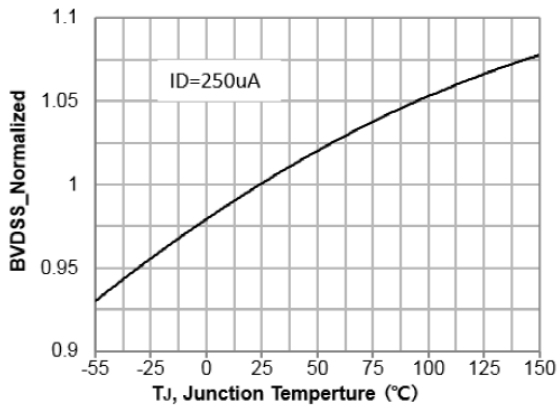


Figure 7. Breakdown Voltage Variation vs Temperature

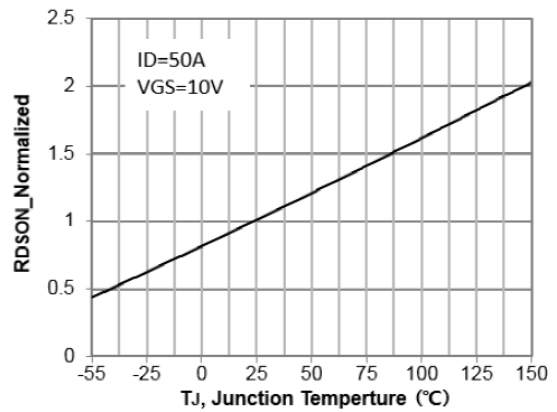


Figure 8. On-Resistance Variation vs Temperature

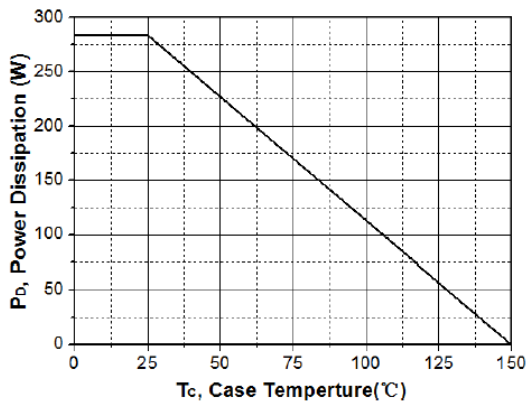


Figure 9. Power Dissipation

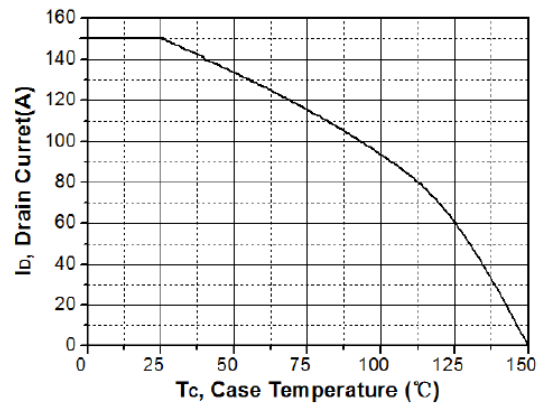


Figure 10. Drain Current Derating

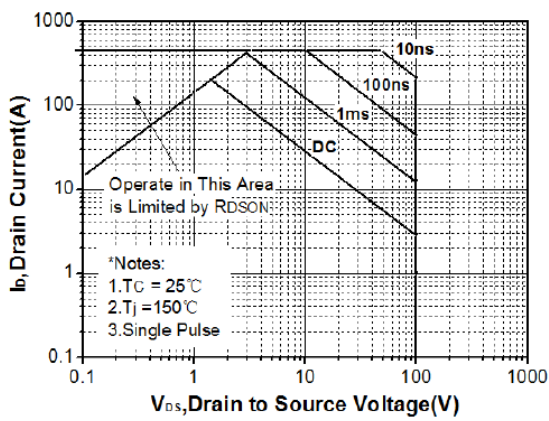


Figure 11. Maximum Safe Operating Area

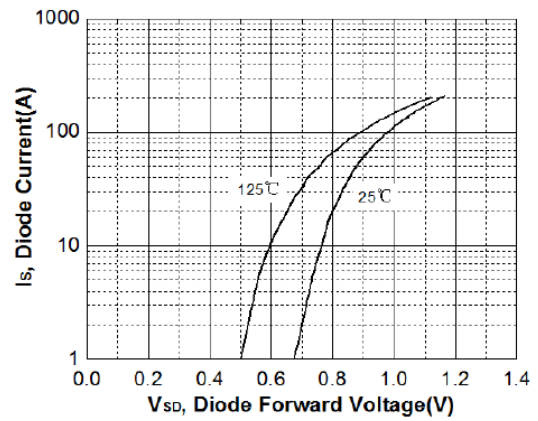
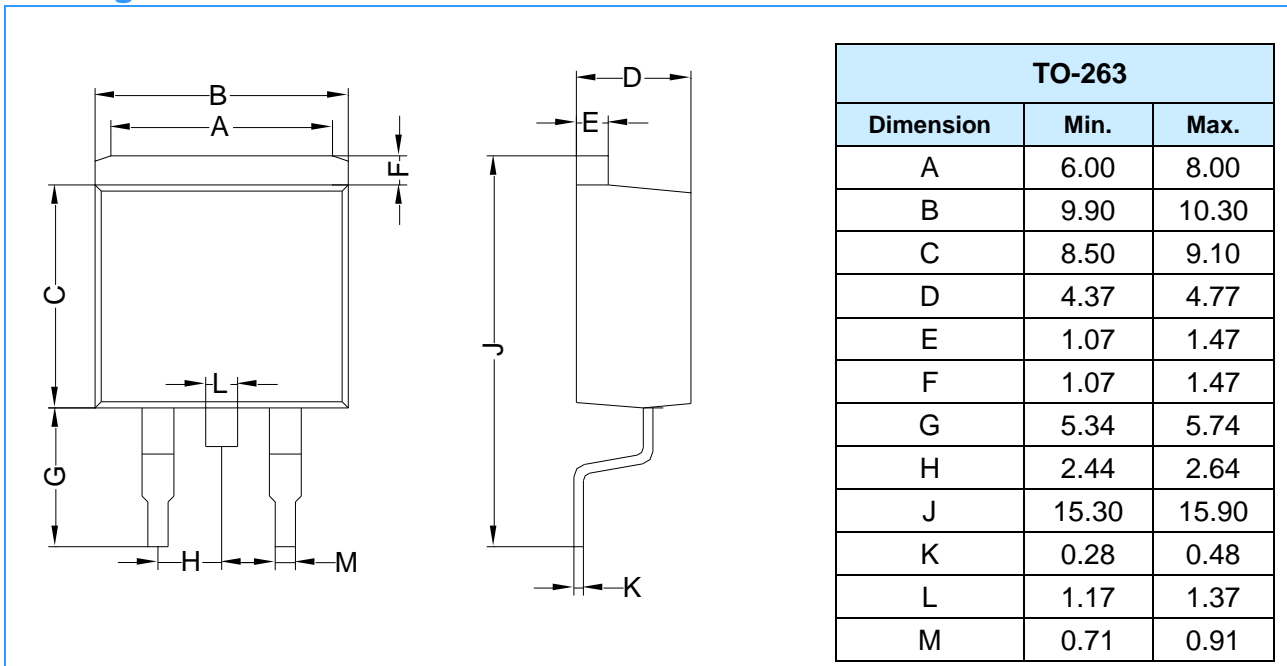
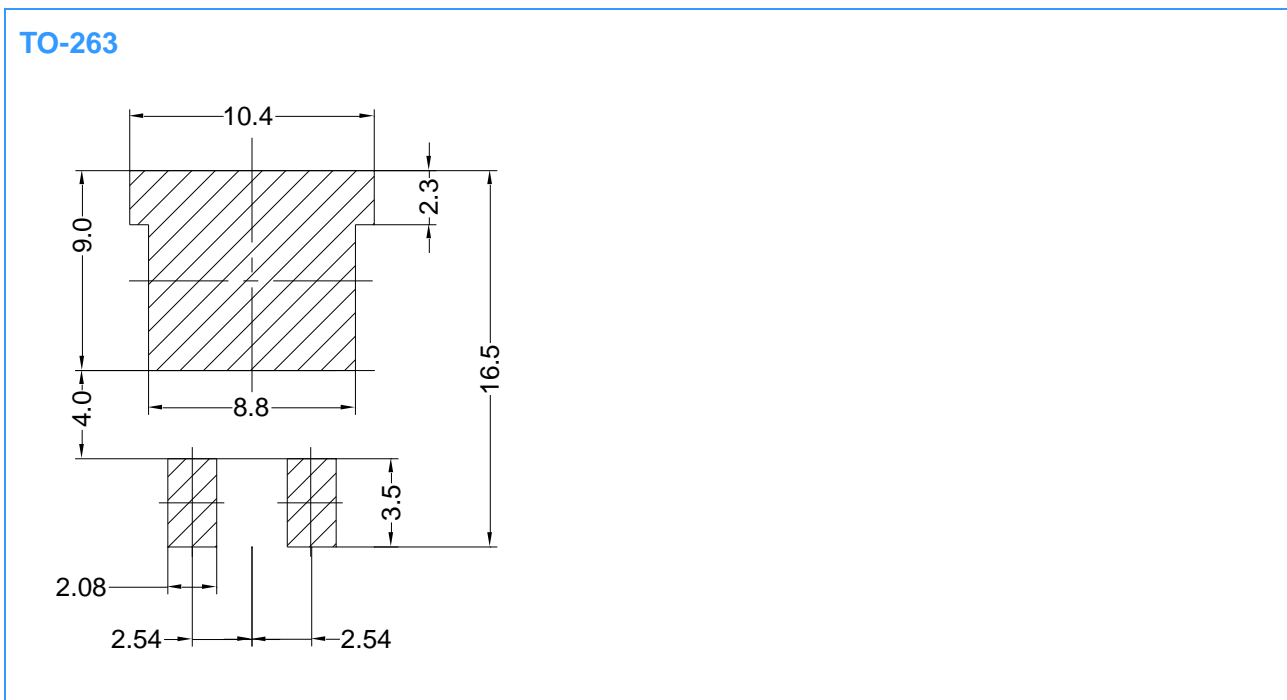


Figure 12. Body-diode Forward Characteristics

Package Outline Dimensions (Unit: mm)



Mounting Pad Layout (Unit: mm)



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